

2020년 2월 13일(목), 10:45~12:00

Room F (스페이스 I, 6층)

B. Patterning 분과

[TF2-B] Patterning Technology: Photolithography and Etch

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| TF2-B-1 10:45~11:00 | Understanding the Exposure Process in the Extreme Ultra Violet Lithography Sang-Kong Kim <i>Department of Science, Hongik University</i> |
| TF2-B-2 11:00~11:30 | [초청] TBA 박종철 <i>삼성전자</i> |
| TF2-B-3 11:30~11:45 | SiO₂ Etching Using Hydrofluoroethers: The Use of Low Global Warming Potential Materials for Plasma Etching Jun-Hyun Kim ¹ and Chang-Koo Kim ² <i>¹Institute of NT-IT Fusion Technology, Ajou University, ²Department of Chemical Engineering and Department of Energy Systems Research, Ajou University</i> |
| TF2-B-4 11:45~12:00 | Influence of Pulse-modulated RF Source Plasma on Etch Characteristic of Nanoscale Patterned Copper Thin Film Using CH₃COOH/Ar Eun Taek Lim, Moon Hwan Cha, and Chee Won Chung <i>Department of Chemical Engineering, Inha University</i> |